

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/808,786	HEAVLIN, WILLIAM D.	
Examiner	Arunkumar P Mehta	Art Unit	Page 1 of 2

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B	US-6,708,073	03-2004	Heavlin, William D.	700/121
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*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
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V	Heavlin et al ("Dual Space Algorithms for Designing Space-Filling Experiments", 1994)		
W	Heavlin et al ("Columnwise Construction of Response Surface Designs", Advanced Micro Devices, 1998)		
X	Wynn ("The Sequential Generation of D-optimum Experimental Designs", 1970)		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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